

Search Notes**Application/Control No.**

10/762,653

Examiner

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Applicant(s)/Patent under Reexamination

TANAKA ET AL.

Art Unit

2134

SEARCHED

Class	Subclass	Date	Examiner
713	189	6/22/2007	ET
713	166, 168	6/22/2007	ET
726	25	6/22/2007	ET
380	28, 37	6/22/2007	ET
380	42	6/22/2007	ET

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO , JPO, DERWENT, IBM TECH DES	6/22/2007	ET
NPL - IEEE XPLOR	6/22/2007	ET
INVENTOR SEARCH - PALM /eDAN	6/22/2007	ET
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	6/22/2007	ET